- 1 1. A method comprising:
- 2 positioning a conductive surface of a
- 3 semiconductor wafer on a conductive polishing pad; and
- 4 providing electrical contact to said surface
- 5 across the pad.
- 1 2. The method of claim 1 including providing a
- 2 plurality of electrodes exposed through said pad.
- 1 3. The method of claim 2 including applying a
- 2 potential of a first polarity to said conductive surface
- 3 through said pad.
- 1 4. The method of claim 3 including coupling said
- 2 electrodes to a potential of a second polarity opposite to
- 3 the first polarity.
- 1 5. The method of claim 2 including providing
- 2 circularly shaped openings in said pad over said
- 3 electrodes.
- 1 6. The method of claim 1 including positioning said
- 2 pad over a conductive platen.
- 1 7. The method of claim 5 including insulating said
- 2 electrode from said pad.

- 1 8. The method of claim 1 including providing said
- 2 pad over a conductive platen and applying potential to said
- 3 film through said pad and platen.
- 1 9. The method of claim 1 including providing
- 2 electrical contact to said surface over the entire extent
- 3 of said surface.
- 1 10. The method of claim 1 including applying pressure
- 2 between said surface and said pad.
- 1 11. The method of claim 1 including providing an
- 2 abrasive fluid between said surface and said pad.
- 1 12. The method of claim 1 including counter rotating
- 2 said pad and said surface.
- 1 13. A polishing pad for an electrochemical polishing
- 2 process comprising:
- a conductive body and a plurality of regularly
- .4 spaced openings through said body; and
- 5 an electrode in said openings connectable to a
- 6 potential, said electrode insulated from said body.
- 1 14. The pad of claim 13 wherein said openings have a
- 2 circular shape.

- 1 15. The pad of claim 13 including an insulator
- 2 between said electrode and said body.
- 1 16. An electrochemical polishing apparatus
- 2 comprising:
- 3 a platen;
- a pad positioned over said platen, said pad being
- 5 conductive; and
- a plurality of electrodes formed within openings
- 7 in said pad, said electrodes being electrically isolated
- 8 from said pad.
- 1 17. The apparatus of claim 16 wherein said platen is
- 2 electrically conductive.
- 1 18. The apparatus of claim 16 including insulators to
- 2 insulate said electrode electrically from said pad.
- 1 19. The apparatus of claim 16 wherein said electrodes
- 2 extend through said pad and said platen.